

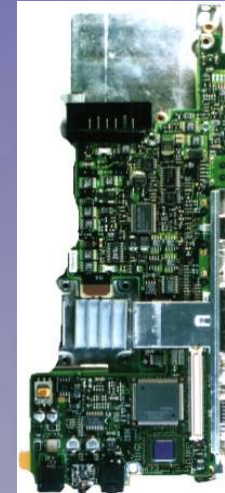


MECetchBOND CZ

Copper Surface Treatment System
for Advanced PWBs



Printed Wiring Board



The Trends of Increased Functionality and Reduced Size of Portable Wireless Products and Routing Densities for PWB



Customers Using MECetchBOND

Japan 95 Users (142 Lines)

Asia 45 Users (73 Lines)

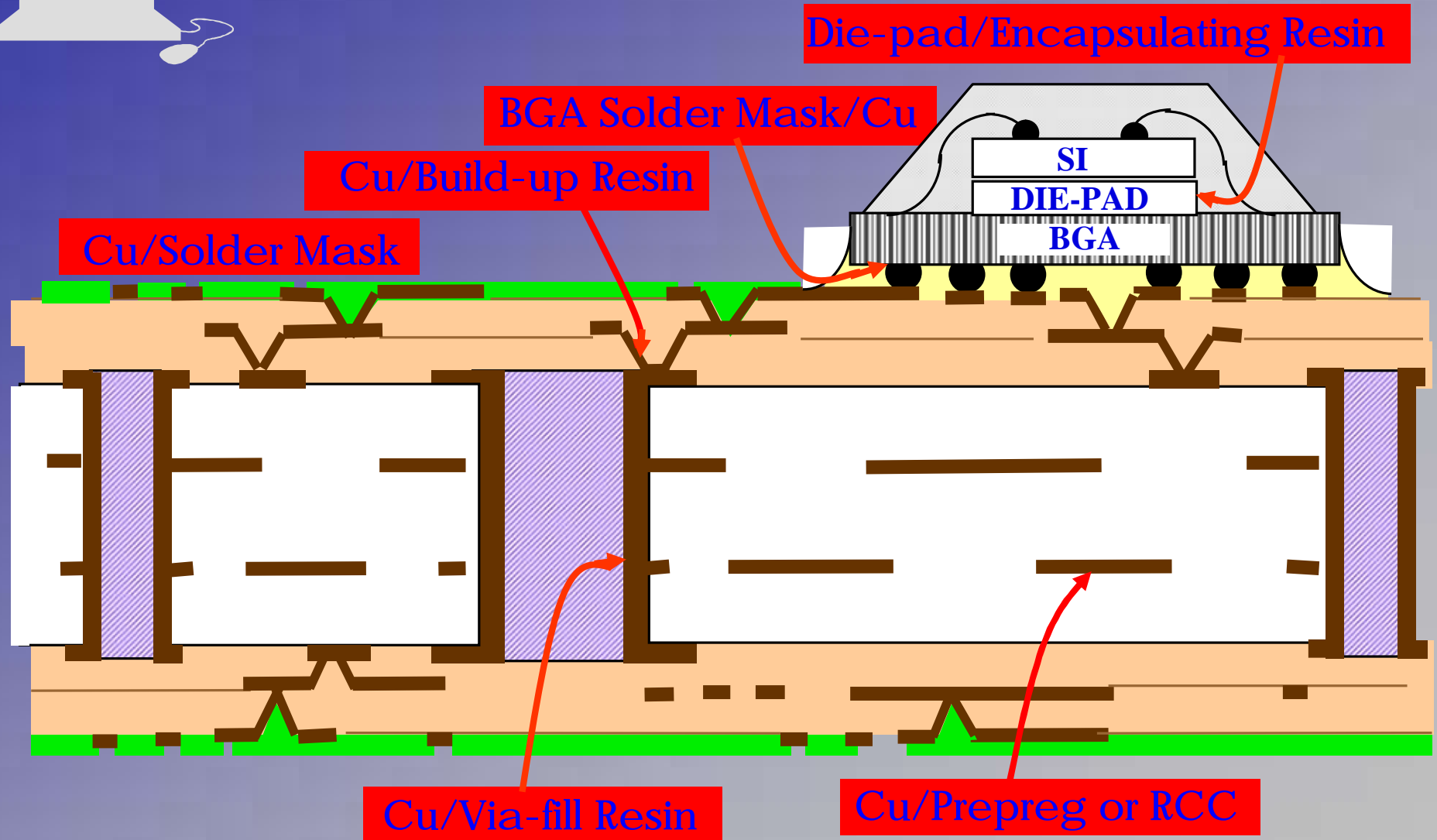
Europe 41 Users (51 Lines)

USA 8 Users (10 Lines)

In 2004



Application of MECetchBOND





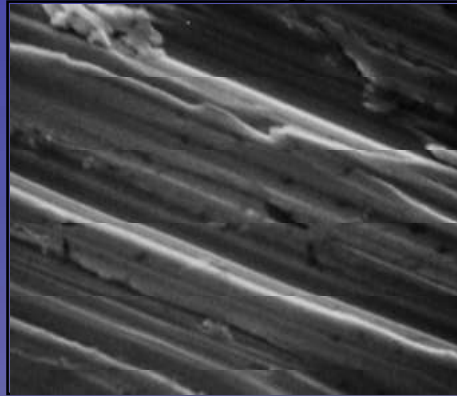
Benefits of MECetchBOND

- **Excellent adhesion to resins**
- **Fully conveyORIZED process**
- **Easy to control**
- **Proven process**
- **Reasonable cost**
- **Environmental friendly**



Copper Surface Topography

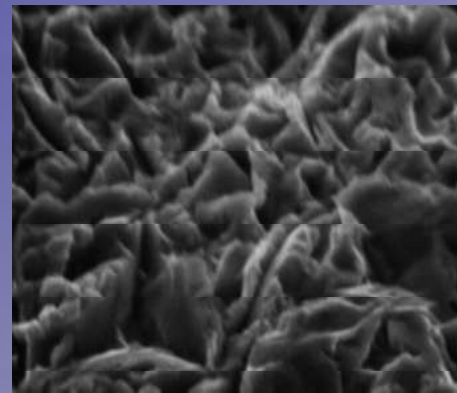
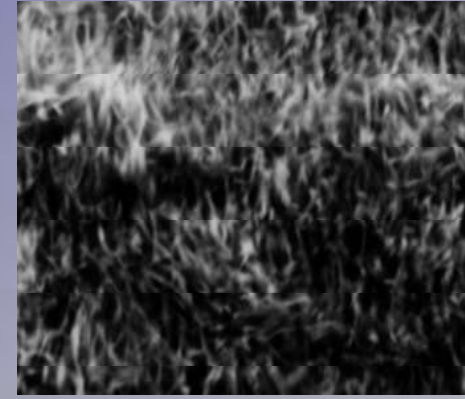
Buff Scrubbing × 5,000



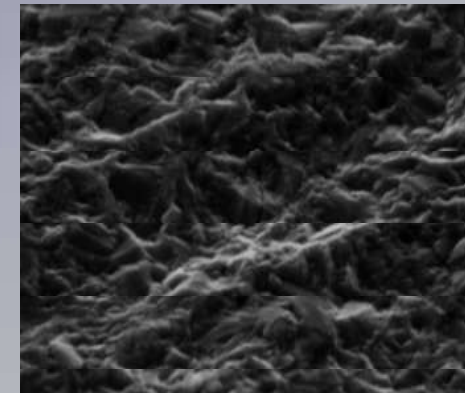
MECetchBOND CZ-8100 × 5,000



Black Oxide × 10,000



Jet Scrubbing × 5,000

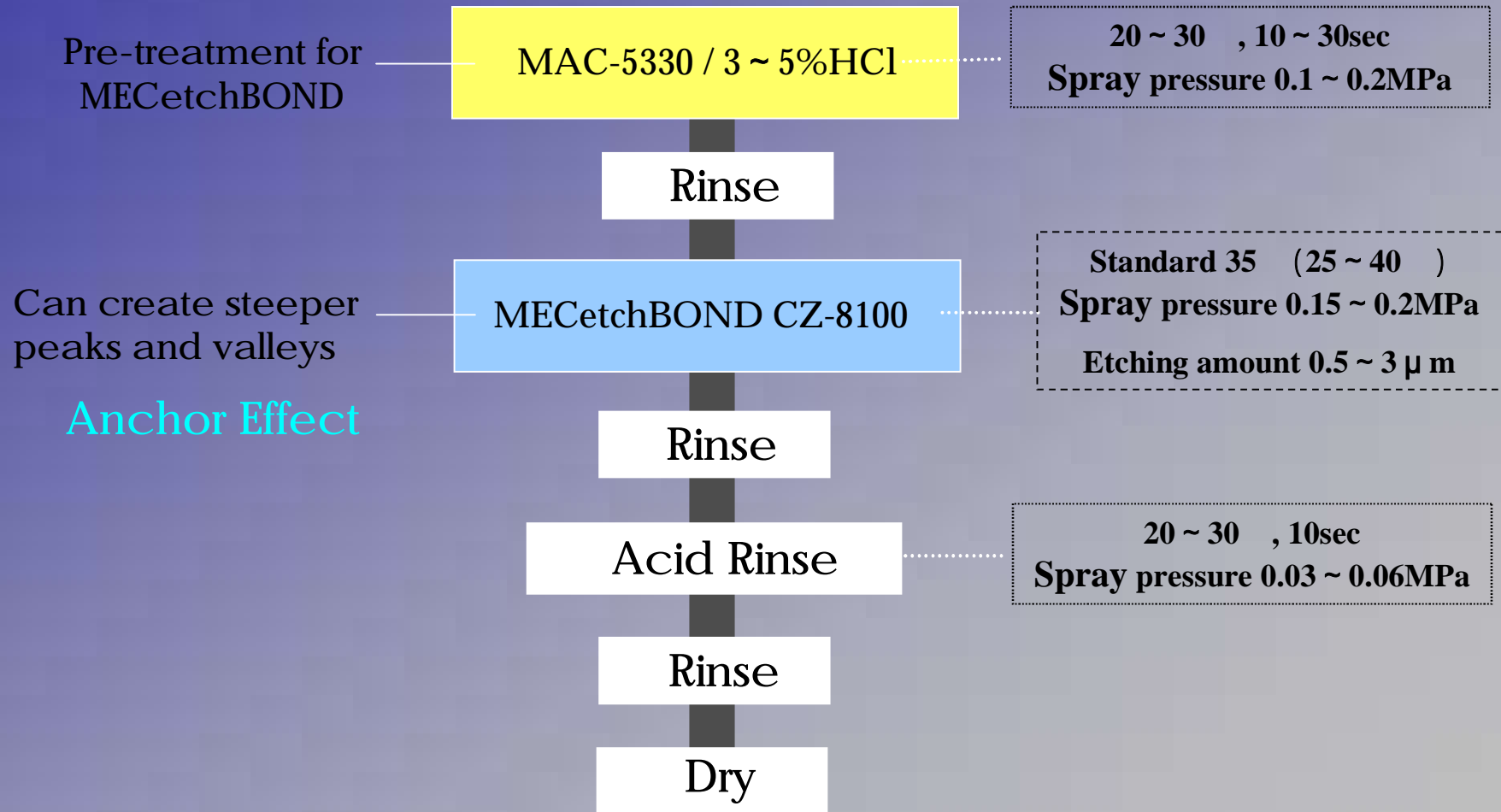


H₂SO₄-H₂O₂ × 5,000

This chemistry is essentially a micro-etching process that roughens the copper surface, resulting in a unique topography.



MECetchBOND Process Flow





Advantages of MECetchBOND

MECetchBOND CZ-8100

- Can Enhance Mechanical Bonding (Anchor Effect)
- Can Give Higher Adhesion
- Simple Control
- Fully conveyORIZED process



Physical Properties & Control

**MECetchBOND
CZ-8100**

	Replenisher CZ-8100R	Make-up Soln. CZ-8100M
Appearance	Colorless - Slight yellow transparent	Blue transparent
Specific Gravity (20)	1.11 ± 0.01	1.13 ± 0.01
pH	3.1 ± 0.5	3.4 ± 0.5

[Usage]

Make-up: Use CZ-8100M as it is.

Replenish: Use CZ-8100R as it is.

[Control]

1. Replenish the dragged-out amount.
2. Cu Concentration (15-30 g/L)
3. Concentration/Dilution (-10- +10%)



CZ-8100 Treated Topography

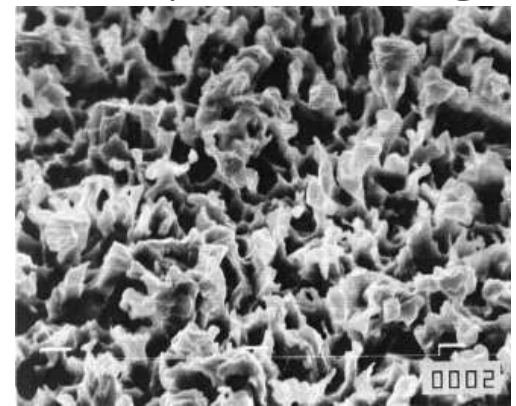
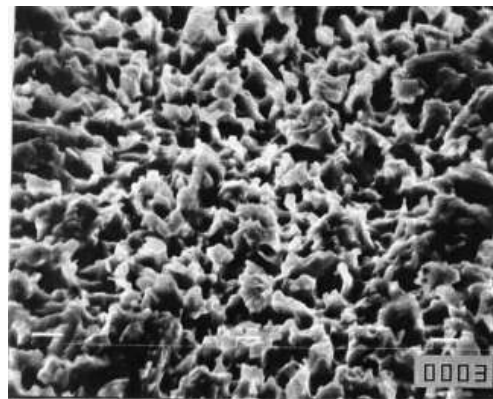
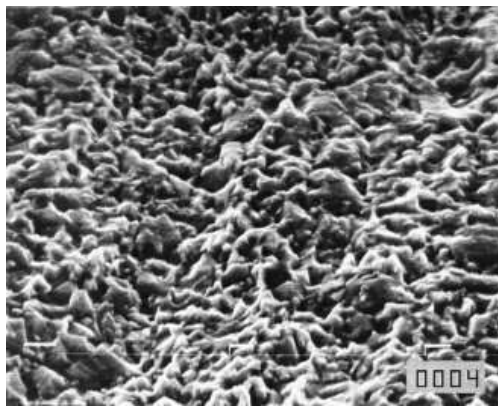
SEM × 5,000

0.5 μm etching

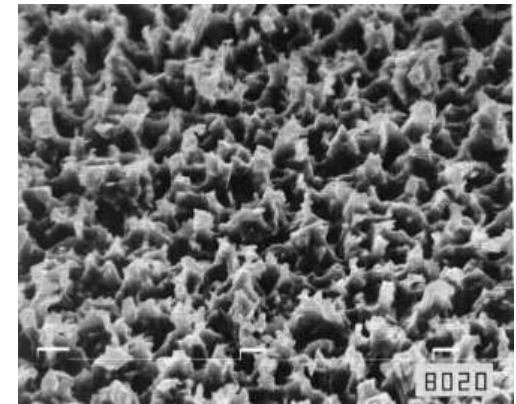
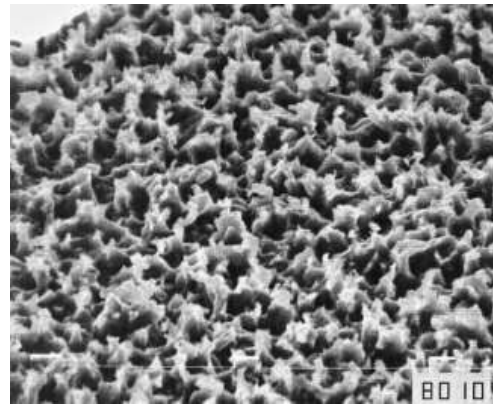
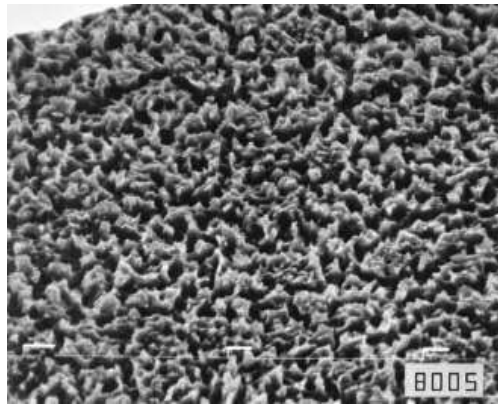
1 μm etching

2 μm etching

CCL



Plated
Copper

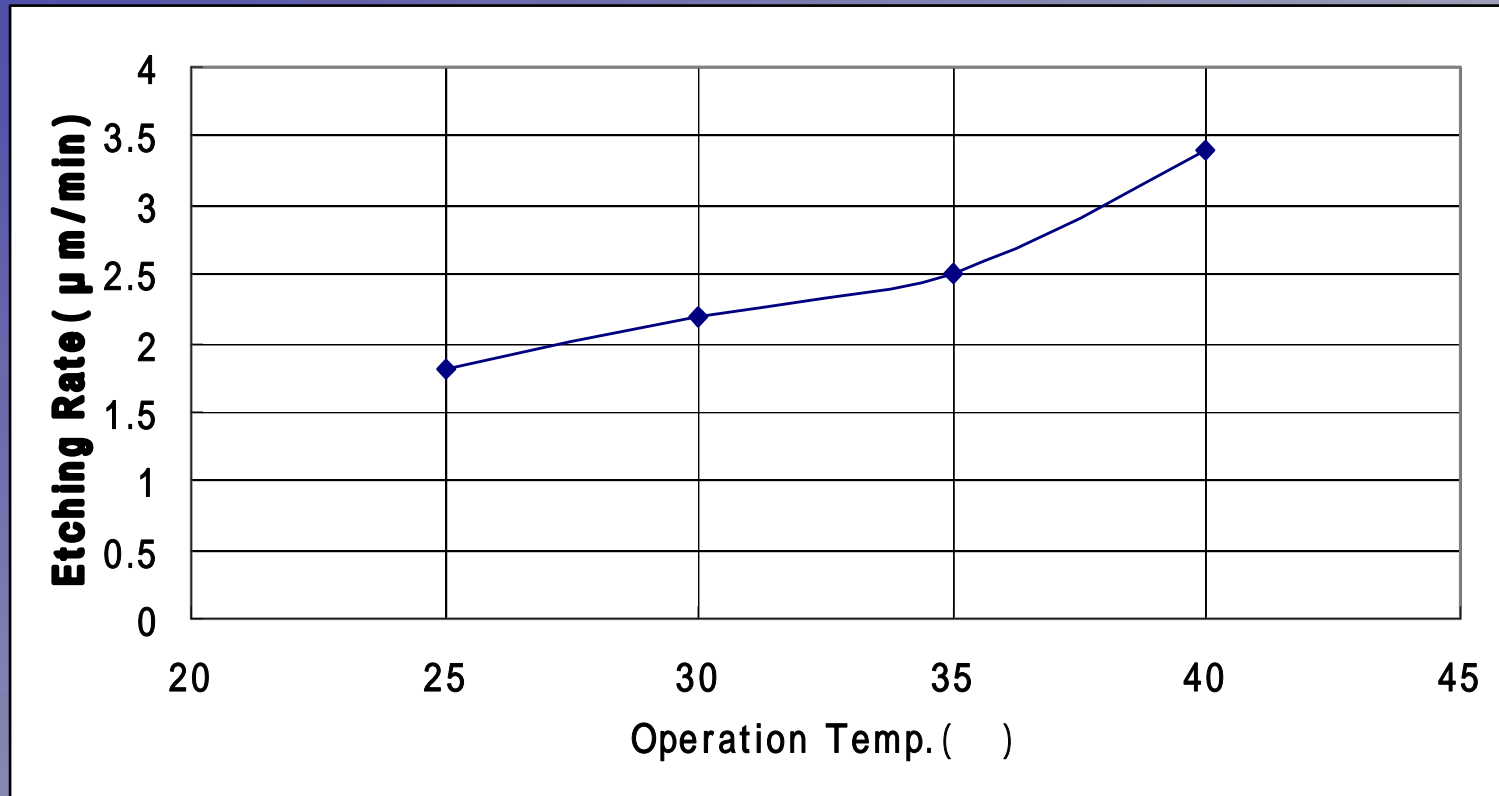


Can decide some roughening variation for some application



Operation Temp. vs. Etching Rate

MEC Test Machine Data

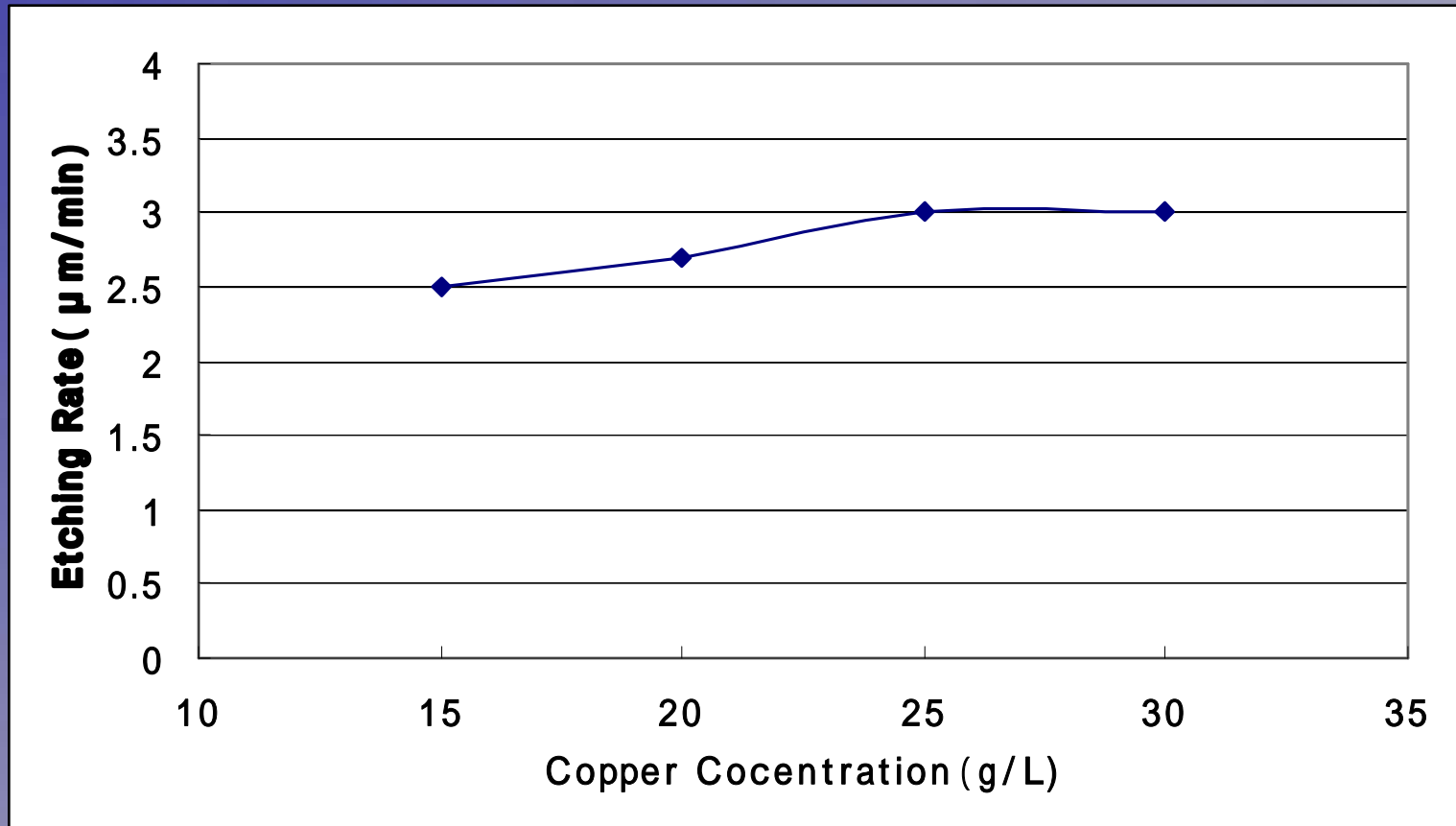


Standard Operation Conditions at 35



Copper Conc. vs. Etching Rate

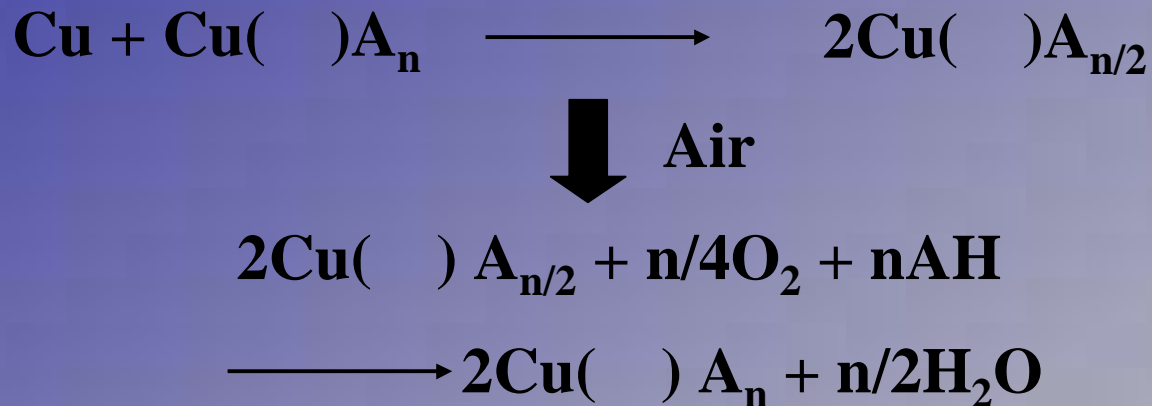
MEC Test Machine Data



Control Range 15 – 30g/L



Etching Mechanism



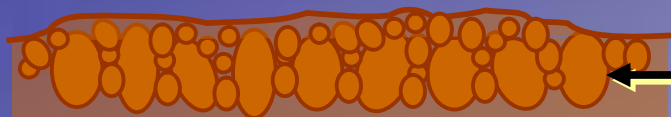
A : Weak Complexer
n : Coordination number

Copper reacts with a $\text{Cu}(\quad)$ complex in the solution to form a $\text{Cu}(\quad)$ complex. The formed $\text{Cu}(\quad)$ complex in the solution reacts with oxygen to generate a $\text{Cu}(\quad)$ complex. Such reactions accelerate dissolving of copper.

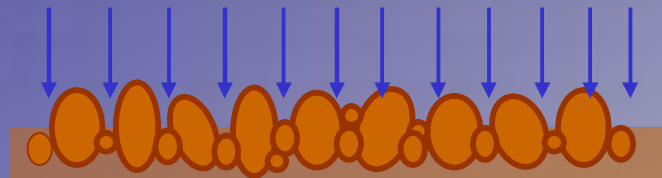


Topography Forming Mechanism

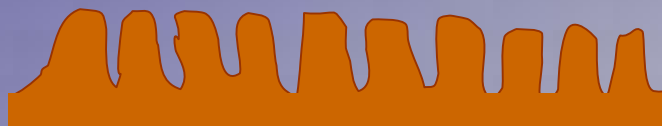
How can such a unique topography be obtained ?



Copper grains



MECetchBOND CZ attacks boundaries faster than crystals.



Well roughened topography is left.



Etching Amount for Applications

- For pretreatment of Solder Mask Printing
 - Etching amount : 0.5 ~ 2.0 μ m
- For pretreatment of Dry Film Lamination
 - Etching amount : 0.5 ~ 1.0 μ m
- For pretreatment of Prepreg Lamination
 - Etching amount : 1.5 ~ 3.0 μ m
- For pretreatment of Micro-via Formation
 - Etching amount : 1.5 ~ 3.0 μ m

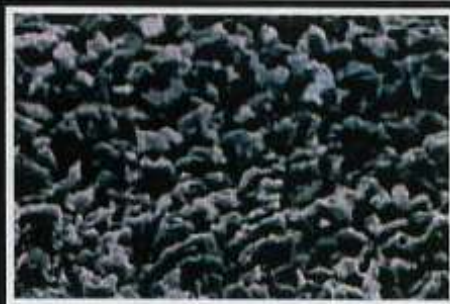


Adhesion (Solder Mask)

- Tape Peel Test-

Solder Mask Printing Cross-cut 3.5% HCl dipping (R.T., 10min)
Rinse&Dry Tape on the cross-cuts Peel

MECetchBOND CZ-8100
(1.5 μ m)



Conventional
Microetchant (2 μ m)

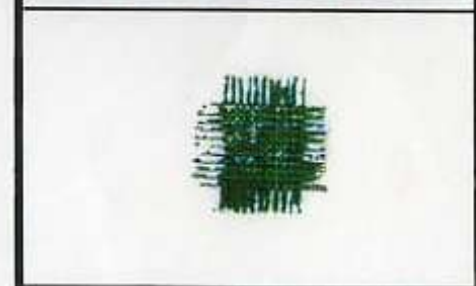


Buff Scrubbing



SEM
 $\times 3,500$

Tape Side



No Peel off of Solder Mask with MECetchBOND Process



Adhesion (Dry Film)

- Tape Peel Test-

Dry Film Lamination Cross-cut 3.5% HCl dipping (R.T., 1 min)
Rinse & Dry Tape on the cross-cuts Peel

MECetchBOND CZ-8100
(1 μ m)



Conventional
Microetchant (2 μ m)

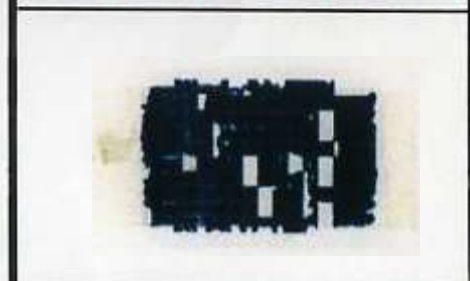
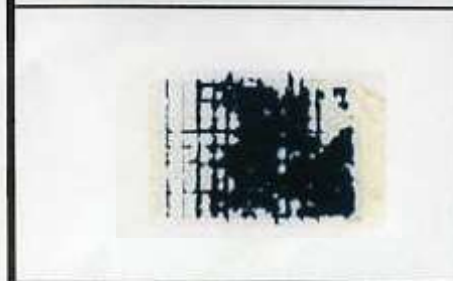
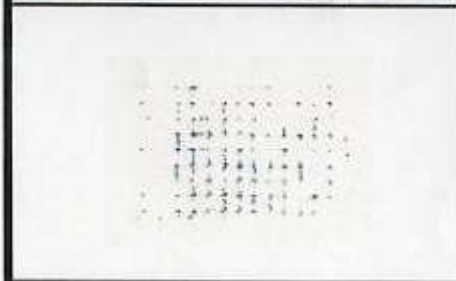


Buff Scrubbing



SEM
 $\times 3,500$

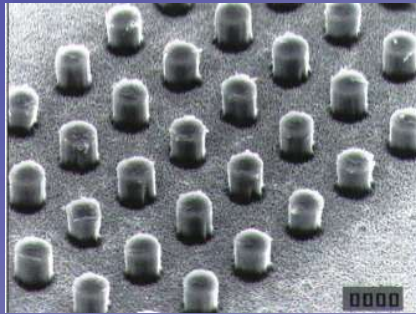
Tape Side



No Peel off of Dry Film with MECetchBOND Process



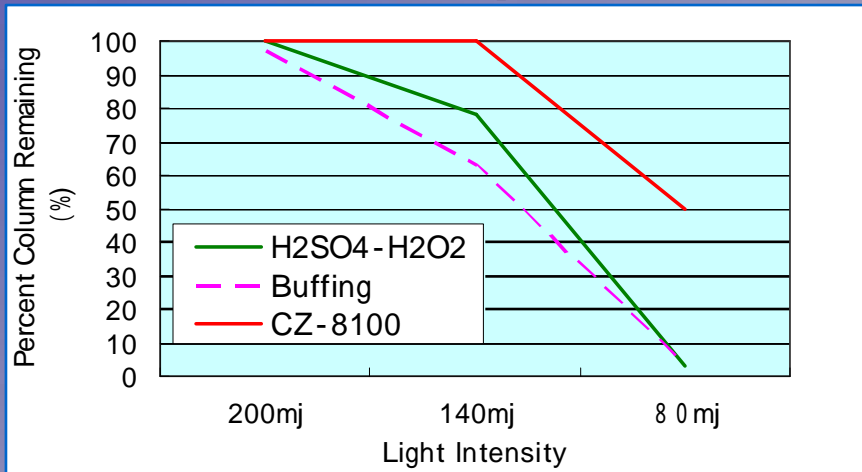
Adhesion (Dry Film)



Column patterns with $10\ \mu\text{m}$ - $30\ \mu\text{m}$ diameter are formed latticedly.
Evaluation Conditions : sparse space / dense space

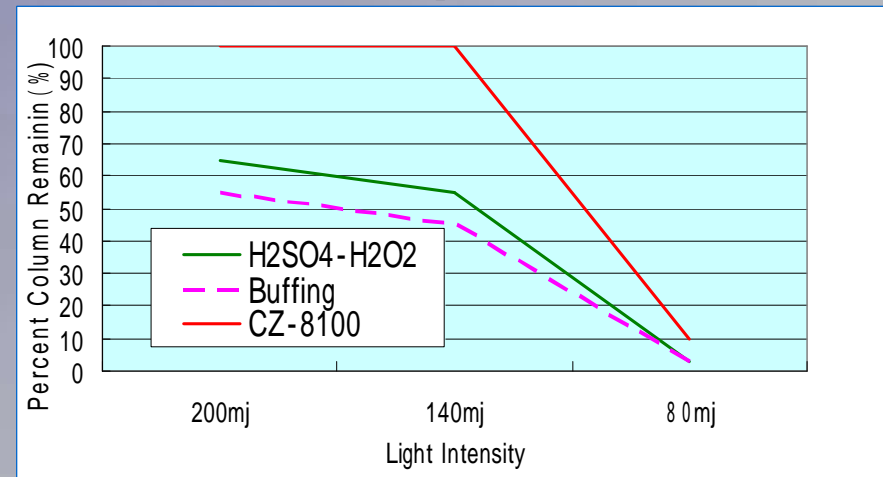
Dense Patterns

Column Pattern Diameter / Space = $20\ \mu\text{m}/20\ \mu\text{m}$



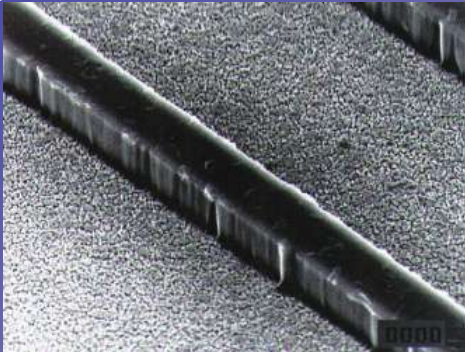
Sparse Patterns

Column Pattern Diameter / Space = $20\ \mu\text{m}/60\ \mu\text{m}$





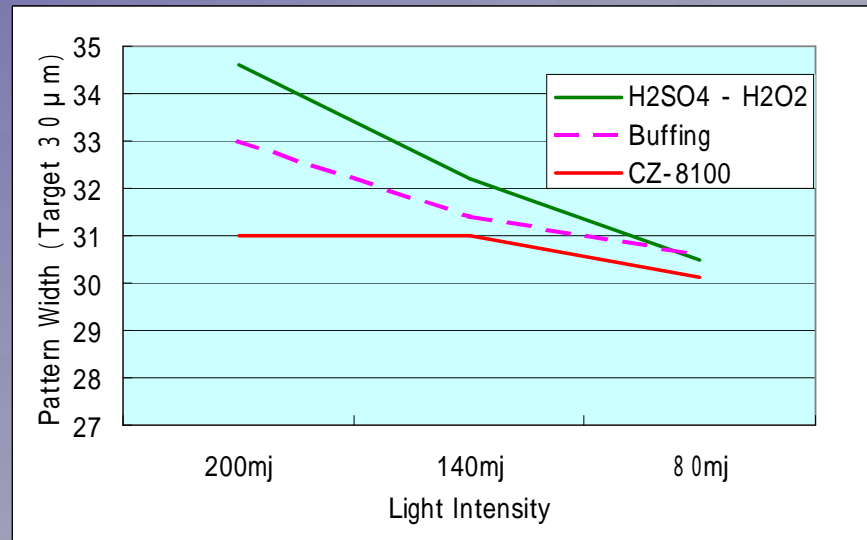
Resolution (Dry Film)



Procedures

- Measure the targeted width and the actual width.
- A condition of light intensity is ;
80mj/cm², 140mj/cm² and 200mj/cm².

Line/Space=30/30 μ m





Summary of MECetchBOND

- Adhesion between copper surface and resin has become more and more important.
- MECetchBOND CZ can enhance mechanical bonding.
- MECetchBOND system can give excellent adhesion and high reliability.
- *MECetchBOND system is what you need for various applications!*